

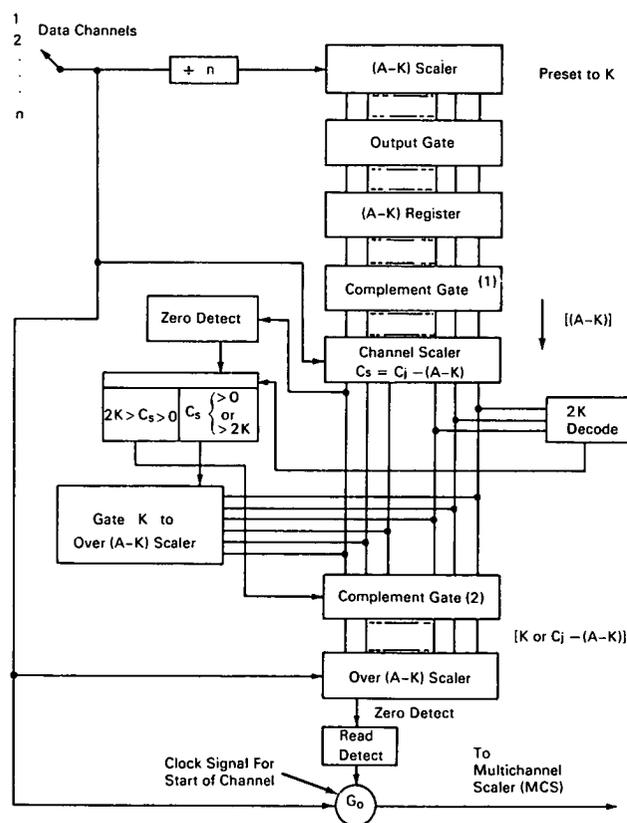


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Digital Filter Suppresses Effects of Nonstatistical Noise Bursts on Multichannel Scaler Digital Averaging Systems



The problem:

To suppress the effects of large, nonstatistical noise bursts on data that have been averaged over many sweeps of a multichannel scaler. Digital data entering a multichannel scaler digital averaging system with a small signal-to-noise ratio will obscure or confuse data previously averaged by the system if the entering data pulse contains large, nonstatistical noise bursts. A

means of filtering out such distorted pulse data is required.

The solution:

A digital noise filter, interposed between the sampled channels and the multichannel scaler digital averaging system, makes use of binary logic circuitry to compare the number of counts per channel (C_j) with the average number of counts per channel (A_m).

(continued overleaf)

If the channel count falls within $A_m \pm K$ ($\pm K$ = preset allowable count fluctuation), the channel count is accepted and passed to the multichannel scaler digital averaging system.

How it's done:

Before operating the digital filter (DF), a value K is chosen as the acceptable fluctuation limits about the average number of counts per channel A_m . The filter consists of four parallel paths: (1) a division scaler set to give one output count for every n input counts (n = number of channels being swept); (2) a channel scaler in which incoming counts for each channel j are accumulated; (3) the "OVER ($A-K$)" scaler which is used to output data to the multichannel scaler; and (4) a gate G_0 to pass the output of the DF to the input of the multichannel scaler (MCS).

Before each sweep of the data channels, the ($A-K$) scaler is preset to \bar{K} , the binary complement of K . At the end of the sweep, the content of this scaler is transferred by a parallel output gate to the ($A-K$) register, and the ($A-K$) scaler is cleared and reset to \bar{K} .

The DF reads each channel for a channel period of T_j during each sweep. At the start of each channel period T_j , the complement of ($A-K$), ($\overline{A-K}$), is non-destructively shifted by the complement gate (1) to the channel scaler. The channel scaler is thus preset to a value $-(A-K)$. The total counts in the channel scaler at the end of each period T_j will be $C_s = C_j - (A-K)$. The incoming counts for a data channel C_j fed to the channel scaler thus advance the scaler contents toward zero. If C_s reaches zero, then C_j exceeds the lower limit ($A-K$). To determine whether or not C_j has exceeded the upper limit ($A+K$), a $2K$ coincidence circuit monitors the channel scaler. If the channel scaler count C_s passes zero but does not pass $2K$, then C_j lies between the limits ($A+K$) and ($A-K$) and the channel information is acceptable. If the count C_s is less than zero or greater than $2K$, the allowable limits have been passed and the data are not acceptable. For $(A-K) < C_j < (A+K)$, the binary complement of the contents of the channel scaler [effectively $C_j - (A-K)$] are passed by complement gate (2) into the "OVER ($A-K$)" scaler. For $(A+K) < C_j < (A-K)$, the complement \bar{K} is shifted into the "OVER ($A-K$)" scaler.

At the start of the next channel period T_{j+1} , gate G_0 is opened and remains so until the "OVER ($A-K$)" scaler is driven to zero. While G_0 is open, either C_j

– ($A-K$) or K (depending on the contents of the scaler) is transferred into channel $j+1$ of the MCS. Thus channel data accumulated in T_j are stored in channel $j+1$.

During T_1 , no previous channel information is available, so channel 1 is used to accumulate the sum of all $(A-K)_m$ for the whole run. Thus for T_1 only, circuitry not shown closes G_0 , permitting the value $A-K$ to enter channel 1 of the MCS if $C_1 > (A-K)$. A small error occurs in the accumulated sum of the $(A-K)_m$ whenever $C_1 < (A-K)$.

Notes:

1. A signal strength of $S > K$ is recorded as K rather than $S+K$. In this case, either the DF is bypassed or K must be large relative to S .
2. For the DF described, C_j (counts accumulated for a given channel in each pass) is not signal plus background $s+b$, but the much smaller number $s+K$.
3. This DF has been constructed with 155 integrated circuit devices and has fluctuation limits from 8 to 768 about the average count (2 figure binary precision).
4. Additional details are contained in Review of Scientific Instruments, vol. 37, no. 6, June 1966, p. 769-771.
5. Inquiries concerning this innovation may be directed to:

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Patent status:

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